

## CLAIMS:

1. A method of determining the position of an object (4) in an image (I), wherein a pattern of marking elements (6), which are not visibly evident individually in the image (I), is attached to the object (4).

5 2. A method as claimed in claim 1, characterized in that the position of the marking elements (6) in the image (I) is determined by a correlation of the image (I) with at least one filter image (M) of the pattern of the marking elements.

3. A method as claimed in claim 2, characterized in that the filter image (M) of  
10 the pattern is transformed relative to the actual pattern of the marking elements.

4. A method as claimed in claim 1, characterized in that the image (I) is generated by means of radioscopy, and the marking elements (6) exhibit a low absorption of the X-rays, the effect of which lies within the noise level of the X-ray image.  
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5. A method as claimed in claim 1, characterized in that the position of at least one further object is determined in the image (I), wherein a second pattern of marking elements, which do not show up individually in the image, is attached to the further object, and wherein the second pattern is different from the first pattern.  
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6. Marking means (5) for attaching to an object (4) in order to determine its position in an image (I), wherein the marking means (5) comprise marking elements (6) arranged in a pattern, which are not visibly evident individually in the image (I).

25 7. Marking means as claimed in claim 6, characterized in that the marking elements (6) are applied to a transparent carrier.

8. Marking means as claimed in claim 6, characterized in that the pattern of marking elements (6) is a two-dimensional maximum-length sequence.

9. An X-ray system, comprising

- An X-ray source (1);

- An X-ray detector (3), which is disposed in the ray path of the X-ray source  
5 (1);

- At least one marking means (5) for attachment to an object (4) located  
between the X-ray source (1) and the X-ray detector (3) in order to determine  
its position in an X-ray image (I), wherein the marking means (5) comprise  
marking elements (6) arranged in a pattern, which are not visibly evident  
10 individually in the X-ray image (I).

- A data processing unit (2) for calculation of the position of the marking means  
(6) in an image (I) generated with the X-ray system.

10. An X-ray system as claimed in claim 9, characterized in that it is set up to

15 implement a method as claimed in at least any one of claims 1 to 5.